L	,	Hits :	Search Text	DB	Time stamp	
Number 1	•		"6025630" 	US-THPUB; EPG; JPG; DERWENT;	2003(02/05) 12:30	•
2		3210	250/396R	IBM TDF USPAT; US 4 3PUB; EPO: JEO; DERGENT; IBM TDF	2003/12/05	
3			("4162403" "4180738" "4554452" "4567369" "5047646" "5144129" "5362829" "5313062" "5396077"	USPAT	2003/02 ^{/05} 12:31	
. 4		6 ,	"5617373").PN. 5047646.URPN.	USPAT	2003/02/05 12:36	
5		3	5302829.URPN.	USEAT	2001,02105 12:11	
ь			("4695725" "4818873" "5047646" "5134288" "5144129" "5654547").PN.	USFAT	2003, 02105 12:37 2003 02101	
-		50638	(electron adj microscope) or (charged adj particle)	USHAT; USHIGPUB; EFC: JIO; DEFWENT;	16:9-	
: : - :	:	43956	(electron adj microscope) or (charged adj particle adj beam)	IBM TDB USLAT; US-FGFUB; EFG: JPO; DEFWENT;	2003-02/01 16:53	
: i =	1	646	((electron adj microscope) or (charged adj particle adj beam)) and (astigmatism)	IFM_TIB USFAT; USFEGFUB; EFO: JFG; DEFWENT;	2001/02/03	
-	i	840	250/305	IBM_TIG USFAT; US-PGFUB; EPO; UFO;	2003/02/01 17:02	
-	!	2627	250/306	DEPWENT; IBM_TDB USFAT; US_PGFUB; EPO; IPO;	+ 2003/00/01 17:13	
-	 - -	1936	i 250/307	DEFWENT: FIBM_TOB USPAT; US-PGPUB; EPO; UPO;	200?/0L/01 17:04	;
-	!	677	250/308	DEPWENT; IBM_TNB USFAT; US-PGFUB; EFF; JPO;	. 2000/02/01 17:4	
: -	:	822	250/309	DEPWENT; IEM_TOB US PAT; US - PGPUB; EPC; JPO;	200:/02/01	
; _		2167	250/310	DEPWENT; IPM_TDB USFAT; US-PGPUB; EPD; IFO; DERWENT; IEM_TDB		

	3171	250/311	USPAT; US-PGPUB; EPO; JPO; DEEWENT;	2003/02/01 17:07	
-	1022	250/396ML	IEM TDB USPAT; US-FGPUB; EPO: JPO; DEFWENT;	2003/02/01 17:08	
-	1570	250/398	IFM_TDB USPAT;	2003/02/01 17:09	
-	2372	250/492.1	IBM TDB USPAT; US-1GPUB; EPO; JPC;	2003/02/01	
-	4131	250/492.2	DEPWENT; IBM_TDE USFAT; USFFGPUB; EPG: JPC; TEPWENT;	2003/02/01 17:13	
- :	144726	watanabe.in.	IBM_TDB USEAT; US-PGPUB; EPO; JPO;	2003/02/01 17:13	
-	; i ; ; ; ; ; ; ; ; ; ; ; ; ; ; ; ; ; ;	<pre>watanabe.in. and (astigmatism or (scanning adj electron adj microscope))</pre>	I EFWENT; I IEM TOB USFAT; US-PGFUB; EPO: JPO; DERWENT:	2003,02,'03 +14:41	
. -		(((electron adj microscope) or (charged adj particle adj beam)) and (astigmatism)) and focal	IBM TIB USPAT; US-PGFUB; EPO; JPO; IERWENT;	2003/02/03 14:49	
! -		(((electron adj microscope) or (charged adj particle adj beam)) and (astigmatism)) and focus	IBM_TDB USPAT; US-PGFUB; EPO; JPO; LEFWENT;	2003/02/04	:
 - 	219	250/49\$3 and diagonal	IBM_TDB USPAT; US-PGPUB; EPU; JPO;	2003/02/05	
-	514	250/3\$2 and diagonal	DEFWENT; IBM_TDB USFAT; US-PGPUB; EPC; JFO; DEFWENT;	2003/02/05 08:56	!
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